

74LVT16374A; 74LVTH16374A

3.3 V 16-bit edge-triggered D-type flip-flop; 3-state

Rev. 10 — 2 April 2012

Product data sheet

1. General description

The 74LVT16374A; 74LVTH16374A are high performance BiCMOS products designed for V_{CC} operation at 3.3 V.

This device is a 16-bit edge-triggered D-type flip-flop featuring non-inverting 3-state outputs. The device can be used as two 8-bit flip-flops or one 16-bit flip-flop. On the positive transition of the clock (nCP), the nQn outputs of the flip-flop take on the logic levels set up at the nDn inputs.

2. Features and benefits

- 16-bit edge-triggered flip-flop
- 3-state buffers
- Output capability: +64 mA and -32 mA
- TTL input and output switching levels
- Input and output interface capability to systems at 5 V supply
- Bus-hold data inputs eliminate the need for external pull-up resistors to hold unused inputs
- Live insertion and extraction permitted
- Power-up reset
- Power-up 3-state
- No bus current loading when output is tied to 5 V bus
- Latch-up protection:
 - ◆ JESD78B Class II exceeds 500 mA
- ESD protection:
 - ◆ HBM JESD22-A114F exceeds 2000 V
 - ◆ MM JESD22-A115-A exceeds 200 V

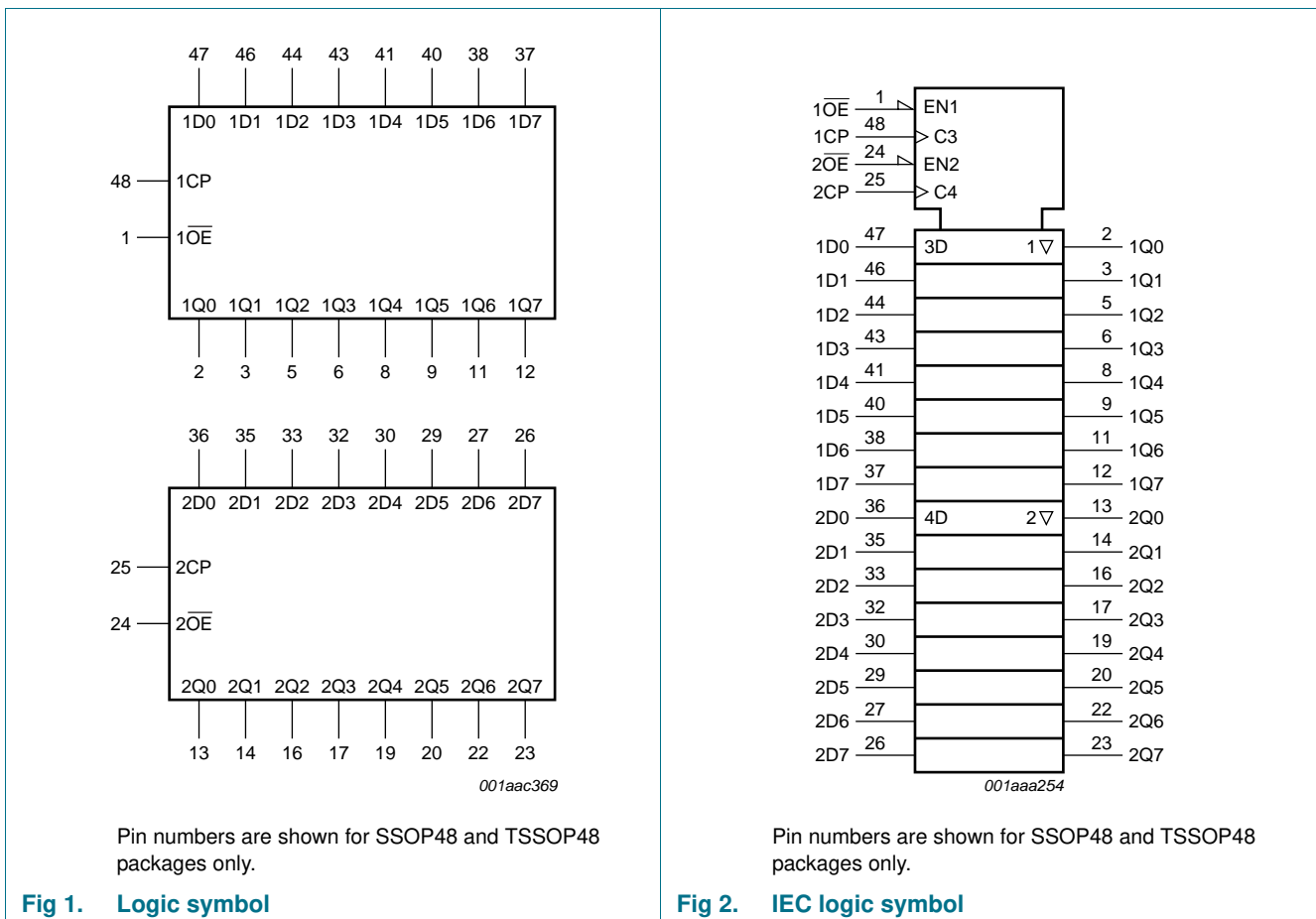


3. Ordering information

Table 1. Ordering information

| Type number | Package | | | Version |
|-----------------------------------|-------------------|---------|---|-----------|
| | Temperature range | Name | Description | |
| 74LVT16374ADL | -40 °C to +85 °C | SSOP48 | plastic shrink small outline package; 48 leads; body width 7.5 mm | SOT370-1 |
| 74LVT16374ADGG 74LVTH16374ADGG | -40 °C to +85 °C | TSSOP48 | plastic thin shrink small outline package; 48 leads; body width 6.1 mm | SOT362-1 |
| 74LVT16374AEV | -40 °C to +85 °C | VFBGA56 | plastic very thin fine-pitch ball grid array package; 56 balls; body 4.5 × 7 × 0.65 mm | SOT702-1 |
| 74LVTH16374ABX | -40 °C to +125 °C | HXQFN60 | plastic compatible thermal enhanced extremely thin quad flat package; no leads; 60 terminals; body 4 × 6 × 0.5 mm | SOT1134-2 |

4. Functional diagram



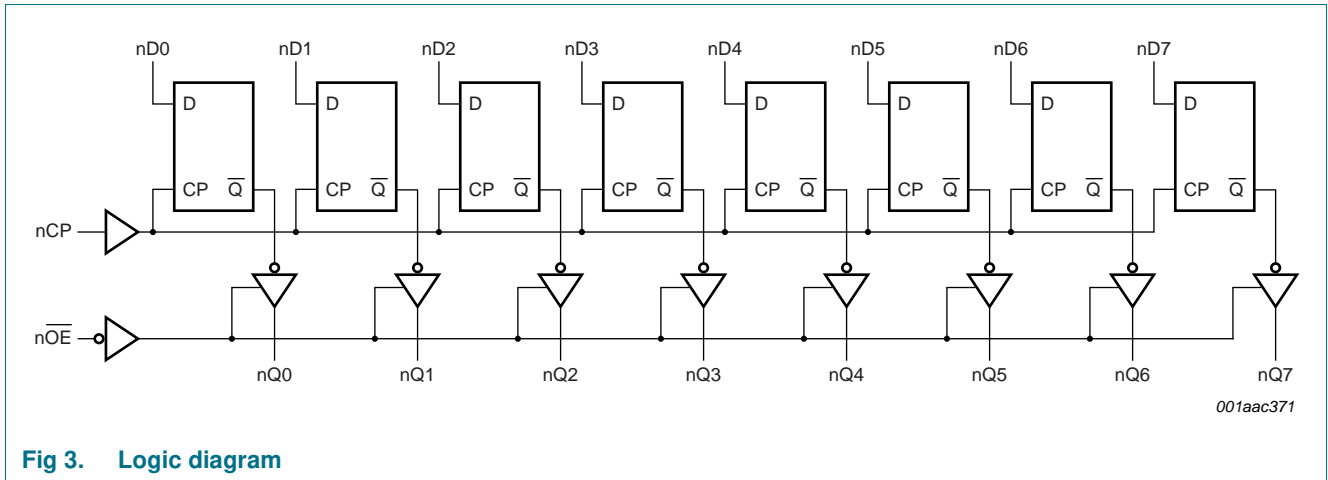


Fig 3. Logic diagram

5. Pinning information

5.1 Pinning

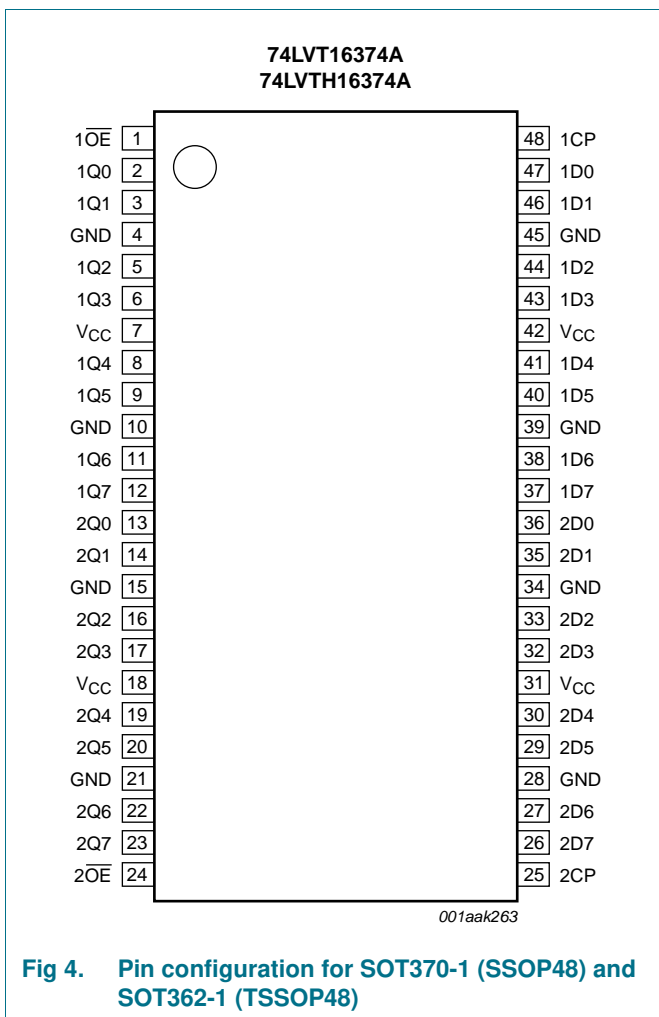


Fig 4. Pin configuration for SOT370-1 (SSOP48) and SOT362-1 (TSSOP48)

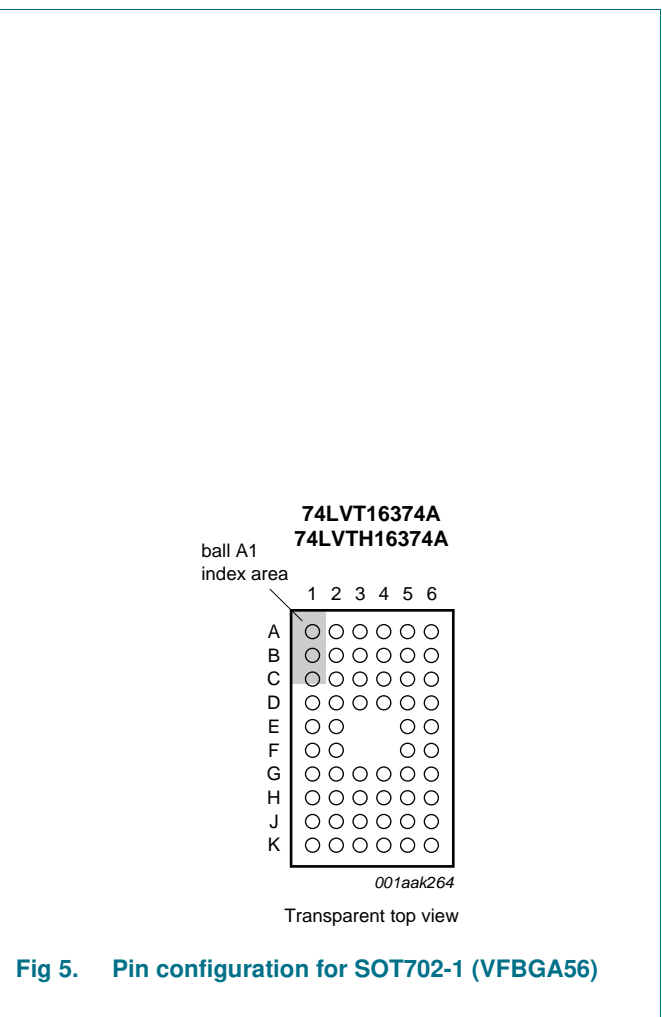
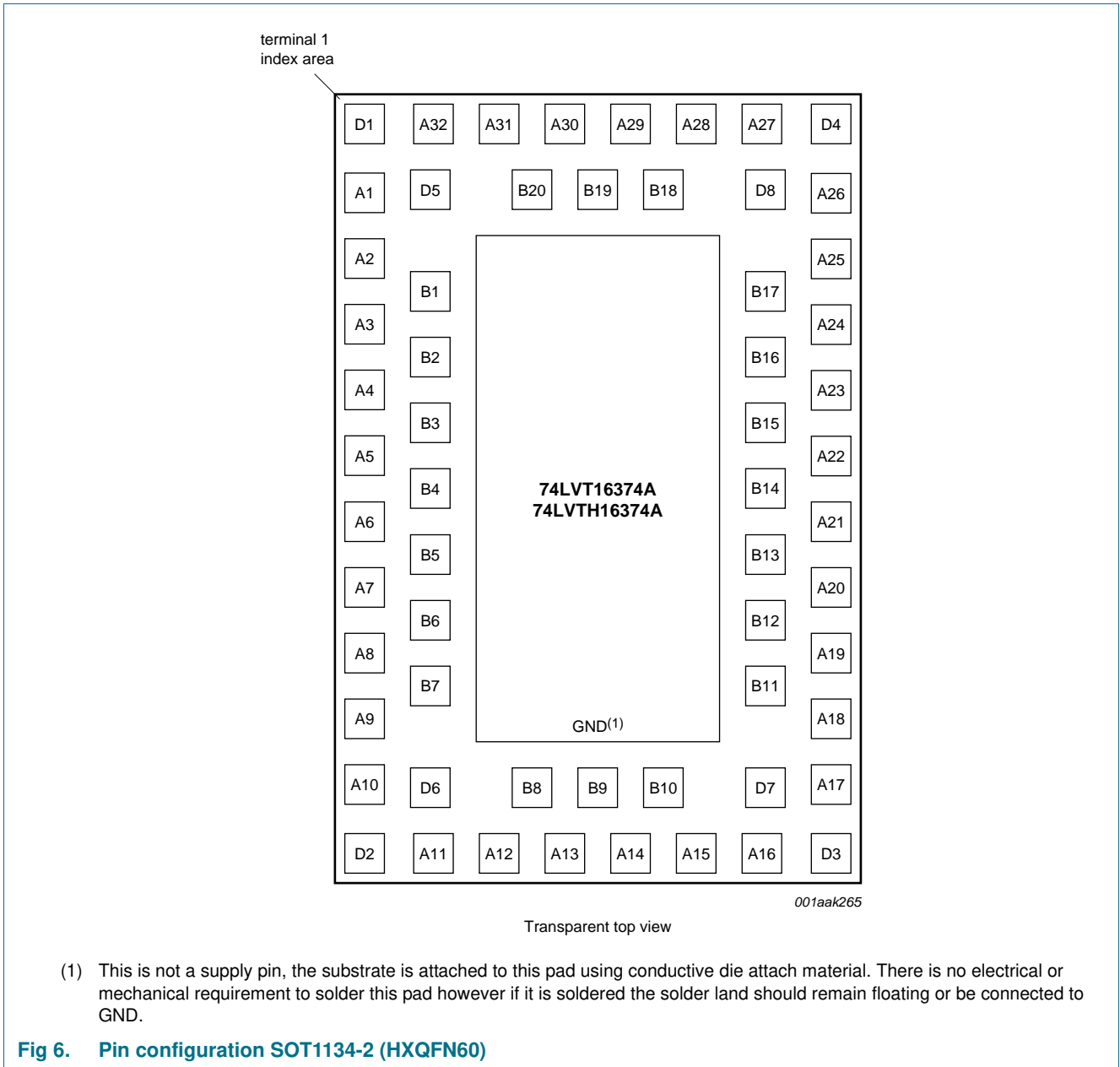


Fig 5. Pin configuration for SOT702-1 (VFPGA56)



5.2 Pin description

Table 2. Pin description

| Symbol | Pin | | | Description |
|----------------------------------|--------------------------------|--------------------------------|--|----------------------------------|
| | SOT370-1 and SOT362-1 | SOT702-1 | SOT1134-2 | |
| $\overline{1OE}, \overline{2OE}$ | 1, 24 | A1, K1 | A30, A13 | output enable input (active LOW) |
| 1CP, 2CP | 48, 25 | A6, K6 | A29, A14 | clock input |
| 1Q0 to 1Q7 | 2, 3, 5, 6, 8, 9, 11, 12 | B2, B1, C2, C1, D2, D1, E2, E1 | B20, A31, D5, D1, A2, B2, B3, A5 | data output |
| 2Q0 to 2Q7 | 13, 14, 16, 17, 19, 20, 22, 23 | F1, F2, G1, G2, H1, H2, J1, J2 | A6, B5, B6, A9, D2, D6, A12, B8 | data output |
| GND | 4, 10, 15, 21, 28, 34, 39, 45 | B3, D3, G3, J3, J4, G4, D4, B4 | A32, A3, A8, A11, A16, A19, A24, A27 | ground (0 V) |
| V _{CC} | 7, 18, 31, 42 | C3, H3, H4, C4 | A1, A10, A17, A26 | supply voltage |
| 1D0 to 1D7 | 47, 46, 44, 43, 41, 40, 38, 37 | B5, B6, C5, C6, D5, D6, E5, E6 | B18, A28, D8, D4, A25, B16, B15, A22 | data input |
| 2D0 to 2D7 | 36, 35, 33, 32, 30, 29, 27, 26 | F6, F5, G6, G5, H6, H5, J6, J5 | A21, B13, B12, A18, D3, D7, A15, B10 | data input |
| n.c. | - | A2, A3, A4, A5, K2, K3, K4, K5 | A4, A7, A20, A23, B1, B4, B7, B9, B11, B14, B17, B19 | not connected |

6. Functional description

Table 3. Function table^[1]

| Operating mode | Input | | | Internal register | Output nQ0 to nQ7 |
|------------------------|-------|-----|-----|-------------------|----------------------|
| | nOE | nCP | nDn | | |
| Load and read register | L | ↑ | l | L | L |
| | L | ↑ | h | H | H |
| Hold | L | NC | X | NC | NC |
| Disable outputs | H | NC | X | NC | Z |
| | H | ↑ | nDn | nDn | Z |

- [1] H = HIGH voltage level;
h = HIGH voltage level one set-up time prior to the HIGH-to-LOW clock transition;
L = LOW voltage level;
l = LOW voltage level one set-up time prior to the HIGH-to-LOW clock transition;
NC = no change;
X = don't care;
Z = high-impedance OFF-state;
↑ = LOW-to-HIGH clock transition.

7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|------------------|-------------------------|-------------------------------------|----------|------|------|
| V _{CC} | supply voltage | | -0.5 | +4.6 | V |
| V _I | input voltage | | [1] -0.5 | +7.0 | V |
| V _O | output voltage | output in OFF-state or HIGH-state | [1] -0.5 | +7.0 | V |
| I _{IK} | input clamping current | V _I < 0 V | -50 | - | mA |
| I _{OK} | output clamping current | V _O < 0 V | -50 | - | mA |
| I _O | output current | output in LOW-state | - | 128 | mA |
| | | output in HIGH-state | -64 | - | mA |
| T _{stg} | storage temperature | | -65 | +150 | °C |
| T _j | junction temperature | | [2] - | 150 | °C |
| P _{tot} | total power dissipation | T _{amb} = -40 °C to +85 °C | | | |
| | | (T)SSOP48 package | [3] - | 500 | mW |
| | | VFPGA56 and HXQFN60 package | [4] - | 1000 | mW |

[1] The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.

[2] The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability.

[3] Above 60 °C the value of P_{tot} derates linearly with 5.5 mW/K.

[4] Above 70 °C the value of P_{tot} derates linearly with 1.8 mW/K.

8. Recommended operating conditions

Table 5. Recommended operating conditions

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|------------------|-------------------------------------|--|-----|-----|-----|------|
| V _{CC} | supply voltage | | 2.7 | - | 3.6 | V |
| V _I | input voltage | | 0 | - | 5.5 | V |
| V _{IH} | HIGH-level input voltage | | 2.0 | - | - | V |
| V _{IL} | LOW-level input voltage | | - | - | 0.8 | V |
| I _{OH} | HIGH-level output current | | -32 | - | - | mA |
| I _{OL} | LOW-level output current | none | - | - | 32 | mA |
| | | current duty cycle ≤ 50 %; f _i ≥ 1 kHz | - | - | 64 | mA |
| T _{amb} | ambient temperature | in free-air | -40 | - | +85 | °C |
| Δt/ΔV | input transition rise and fall rate | outputs enabled | - | - | 10 | ns/V |

9. Static characteristics

Table 6. Static characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

| Symbol | Parameter | Conditions | Min | Typ ^[1] | Max | Unit | |
|---|------------------------------------|---|-----------------------|--------------------|------|------|----|
| T_{amb} = -40 °C to +85 °C | | | | | | | |
| V _{IK} | input clamping voltage | V _{CC} = 2.7 V; I _{IK} = -18 mA | -1.2 | -0.85 | - | V | |
| V _{OH} | HIGH-level output voltage | I _{OH} = -100 μA; V _{CC} = 2.7 V to 3.6 V | V _{CC} - 0.2 | V _{CC} | - | V | |
| | | I _{OH} = -8 mA; V _{CC} = 2.7 V | 2.4 | 2.5 | - | V | |
| | | I _{OH} = -32 mA; V _{CC} = 3.0 V | 2.0 | 2.3 | - | V | |
| V _{OL} | LOW-level output voltage | V _{CC} = 2.7 V | | | | | |
| | | I _{OL} = 100 μA | - | 0.07 | 0.2 | V | |
| | | I _{OL} = 24 mA | - | 0.3 | 0.5 | V | |
| | | V _{CC} = 3.0 V | | | | | |
| | | I _{OL} = 16 mA | - | 0.25 | 0.4 | V | |
| | | I _{OL} = 32 mA | - | 0.3 | 0.5 | V | |
| V _{OL(pu)} | power-up LOW-level output voltage | I _{OL} = 64 mA | - | 0.4 | 0.55 | V | |
| | | V _{CC} = 3.6 V; I _O = 1 mA; V _I = V _{CC} or GND | [2] | - | 0.1 | 0.55 | V |
| | | | | | | | |
| I _I | input leakage current | control pins | | | | | |
| | | V _{CC} = 3.6 V; V _I = V _{CC} or GND | - | 0.1 | ±1 | μA | |
| | | V _{CC} = 0 V or 3.6 V; V _I = 5.5 V | - | 0.4 | 10 | μA | |
| | | input data pins | [3] | | | | |
| | | V _{CC} = 0 V or 3.6 V; V _I = 5.5 V | - | 0.4 | 10 | μA | |
| | | V _{CC} = 3.6 V; V _I = V _{CC} | - | 0.1 | 1 | μA | |
| I _{OFF} | power-off leakage current | V _{CC} = 3.6 V; V _I = 0 V | -5 | -0.4 | - | μA | |
| | | V _{CC} = 0 V; V _I or V _O = 0 V to 4.5 V | - | 0.1 | ±100 | μA | |
| | | | | | | | |
| I _{BHL} | bus hold LOW current | V _{CC} = 3 V; V _I = 0.8 V | 75 | 135 | - | μA | |
| I _{BHH} | bus hold HIGH current | V _{CC} = 3 V; V _I = 2.0 V | - | -135 | -75 | μA | |
| I _{BHLO} | bus hold LOW overdrive current | input data pins; V _I = 0 V to 3.6 V; V _{CC} = 3.6 V | [4] | 500 | - | μA | |
| | | | | | | | |
| I _{BHHO} | bus hold HIGH overdrive current | input data pins; V _I = 0 V to 3.6 V; V _{CC} = 3.6 V | [4] | - | -500 | μA | |
| | | | | | | | |
| I _{LO} | output leakage current | output in HIGH-state when V _O > V _{CC} ; V _O = 5.5 V; V _{CC} = 3.0 V | - | 50 | 125 | μA | |
| I _{O(pu/pd)} | power-up/power-down output current | V _{CC} ≤ 1.2 V; V _O = 0.5 V to V _{CC} ; V _I = GND or V _{CC} ; nOE = don't care | [5] | - | 1 | ±100 | μA |
| I _{OZ} | OFF-state output current | V _{CC} = 3.6 V; V _I = V _{IH} or V _{IL} | | | | | |
| | | output HIGH: V _O = 3.0 V | - | 0.5 | 5 | μA | |
| | | output LOW: V _O = 0.5 V | -5 | 0.5 | - | μA | |
| I _{CC} | supply current | V _{CC} = 3.6 V; V _I = GND or V _{CC} ; I _O = 0 A | | | | | |
| | | outputs HIGH | - | 0.07 | 0.12 | mA | |
| | | outputs LOW | - | 4.0 | 6.0 | mA | |
| | | outputs disabled | [6] | - | 0.07 | 0.12 | mA |

Table 6. Static characteristics ...continued

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

| Symbol | Parameter | Conditions | Min | Typ ^[1] | Max | Unit |
|-----------------|---------------------------|--|-------|--------------------|-----|------|
| ΔI_{CC} | additional supply current | per input pin; $V_{CC} = 3.0$ V to 3.6 V; one input at $V_{CC} - 0.6$ V, other inputs at V_{CC} or GND | [7] - | 0.1 | 0.2 | mA |
| C_I | input capacitance | input pins; $V_I = 0$ V or 3.0 V | - | 3 | - | pF |
| C_O | output capacitance | output pins nQn; outputs disabled; $V_O = 0$ V or V_{CC} | - | 9 | - | pF |

[1] Typical values are measured at $V_{CC} = 3.3$ V and at $T_{amb} = 25$ °C.

[2] For valid test results, data must not be loaded into the flips-flops (or latches) after applying power.

[3] Unused pins at V_{CC} or GND.

[4] This is the bus hold overdrive current required to force the input to the opposite logic state.

[5] This parameter is valid for any V_{CC} between 0 V and 1.2 V with a transition time of up to 10 ms. From $V_{CC} = 1.2$ V to $V_{CC} = 3.3$ V \pm 0.3 V a transition time of 100 μ s is permitted. This parameter is valid for $T_{amb} = 25$ °C only.[6] I_{CC} is measured with outputs pulled to V_{CC} or GND.[7] This is the increase in supply current for each input at the specified voltage level other than V_{CC} or GND.

10. Dynamic characteristics

Table 7. Dynamic characteristicsVoltages are referenced to GND (ground = 0 V); for test circuit see [Figure 10](#).

| Symbol | Parameter | Conditions | Min | Typ ^[1] | Max | Unit |
|---|-------------------------------------|---|-----|--------------------|-----|------|
| $T_{amb} = -40$ °C to $+85$ °C | | | | | | |
| f_{max} | maximum frequency | nCP; $V_{CC} = 3.3$ V \pm 0.3 V; see Figure 7 | 150 | - | - | MHz |
| t_{PLH} | LOW to HIGH propagation delay | nCP to nQn; see Figure 7 | | | | |
| | | $V_{CC} = 3.3$ V \pm 0.3 V | 1.5 | 2.9 | 5.0 | ns |
| | | $V_{CC} = 2.7$ V | - | - | 5.6 | ns |
| t_{PHL} | HIGH to LOW propagation delay | nCP to nQn; see Figure 7 | | | | |
| | | $V_{CC} = 3.3$ V \pm 0.3 V | 1.5 | 3.0 | 5.0 | ns |
| | | $V_{CC} = 2.7$ V | - | - | 5.6 | ns |
| t_{PZH} | OFF-state to HIGH propagation delay | \overline{nOE} to nQn; see Figure 8 | | | | |
| | | $V_{CC} = 3.3$ V \pm 0.3 V | 1.5 | 3.2 | 4.8 | ns |
| | | $V_{CC} = 2.7$ V | - | - | 6.0 | ns |
| t_{PZL} | OFF-state to LOW propagation delay | \overline{nOE} to nQn; see Figure 8 | | | | |
| | | $V_{CC} = 3.3$ V \pm 0.3 V | 1.5 | 3.0 | 4.6 | ns |
| | | $V_{CC} = 2.7$ V | - | - | 5.2 | ns |
| t_{PHZ} | HIGH to OFF-state propagation delay | \overline{nOE} to nQn; see Figure 8 | | | | |
| | | $V_{CC} = 3.3$ V \pm 0.3 V | 1.5 | 3.9 | 5.4 | ns |
| | | $V_{CC} = 2.7$ V | - | - | 6.0 | ns |
| t_{PLZ} | LOW to OFF-state propagation delay | \overline{nOE} to nQn; see Figure 8 | | | | |
| | | $V_{CC} = 3.3$ V \pm 0.3 V | 1.5 | 3.4 | 4.6 | ns |
| | | $V_{CC} = 2.7$ V | - | - | 5.0 | ns |

Table 7. Dynamic characteristics ...continued

Voltages are referenced to GND (ground = 0 V); for test circuit see [Figure 10](#).

| Symbol | Parameter | Conditions | Min | Typ ^[1] | Max | Unit |
|-----------------|-------------|---|-----|--------------------|-----|------|
| t _{su} | set-up time | nDn to nCP; HIGH or LOW; see Figure 9 | [2] | | | |
| | | V _{CC} = 3.3 V ± 0.3 V | 2.0 | 0.7 | - | ns |
| | | V _{CC} = 2.7 V | 2.0 | - | - | ns |
| t _h | hold time | nDn to nCP; HIGH or LOW; see Figure 9 | [3] | | | |
| | | V _{CC} = 3.3 V ± 0.3 V | 0.8 | 0 | - | ns |
| | | V _{CC} = 2.7 V | 0.1 | - | - | ns |
| t _w | pulse width | nCP HIGH; see Figure 7 | [4] | | | |
| | | V _{CC} = 3.3 V ± 0.3 V | 1.5 | 0.6 | - | ns |
| | | V _{CC} = 2.7 V | 1.5 | - | - | ns |
| | | nCP LOW; see Figure 7 | | | | |
| | | V _{CC} = 3.3 V ± 0.3 V | 3.0 | 1.6 | - | ns |
| | | V _{CC} = 2.7 V | 3.0 | - | - | ns |

[1] All typical values are at V_{CC} = 3.3 V and T_{amb} = 25 °C.

[2] t_{su} is the same as t_{su(H)} and t_{su(L)}.

[3] t_h is the same as t_{h(H)} and t_{h(L)}.

[4] t_w is the same as t_{w(H)} and t_{w(L)}.

11. Waveforms

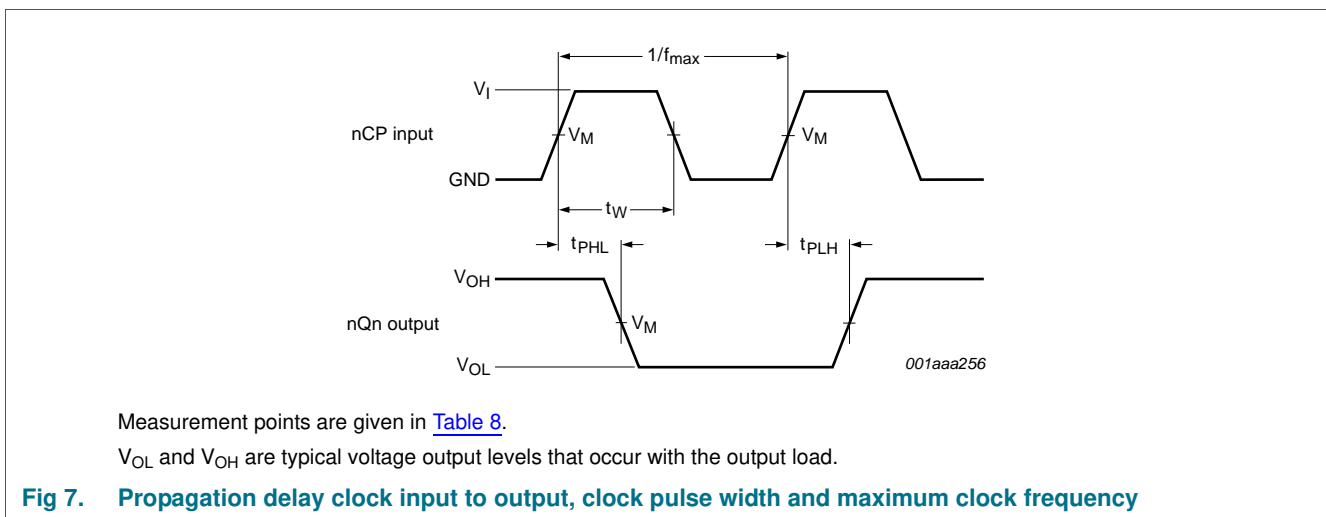
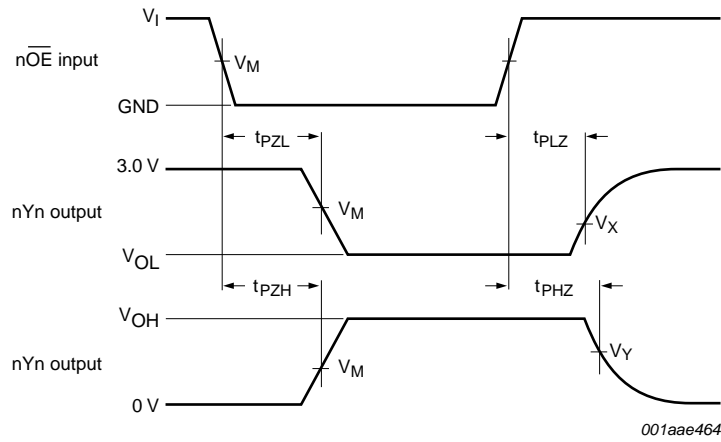


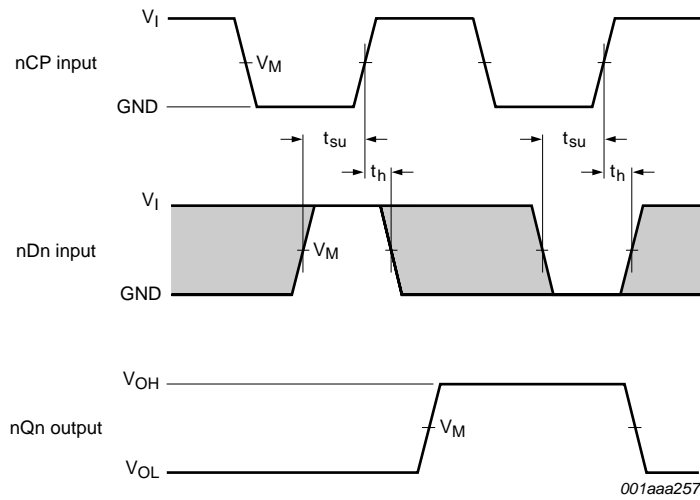
Table 8. Measurement points

| Input | Output | | |
|----------------|----------------|-------------------------|-------------------------|
| V _M | V _M | V _X | V _Y |
| 1.5 V | 1.5 V | V _{OL} + 0.3 V | V _{OH} - 0.3 V |



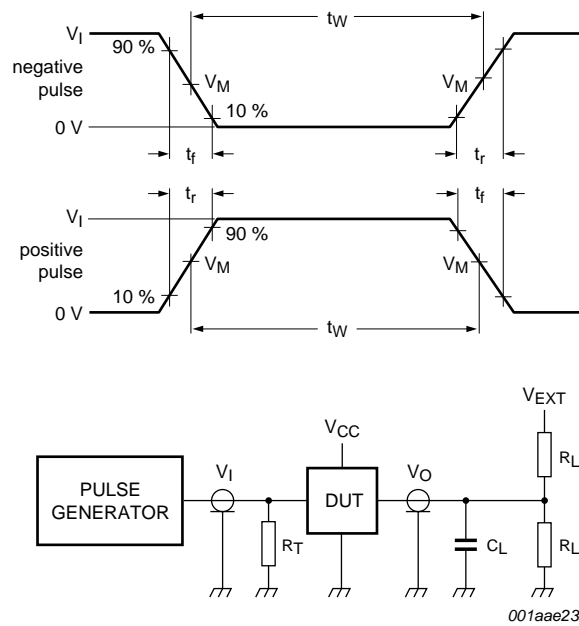
Measurements points are given in [Table 8](#).
 V_{OL} and V_{OH} are typical voltage output levels that occur with the output load.

Fig 8. Enable and disable times



Measurement points are given in [Table 8](#).
 V_{OL} and V_{OH} are typical voltage output levels that occur with the output load.
Remark: The shaded areas indicate when the input is permitted to change for predictable output performance.

Fig 9. Data set-up and hold times



Test data is given in [Table 9](#).

Definitions test circuit:

R_L = Load resistance.

C_L = Load capacitance including jig and probe capacitance.

R_T = Termination resistance should be equal to output impedance Z_o of the pulse generator.

V_{EXT} = Test voltage for switching times.

Fig 10. Test circuit for measuring switching times

Table 9. Test data

| Input | | | | Load | | V_{EXT} | | |
|-------|---------------|--------|---------------|-------|--------------|--------------------|--------------------|--------------------|
| V_I | f_i | t_W | t_r, t_f | C_L | R_L | t_{PHZ}, t_{PZH} | t_{PLZ}, t_{PZL} | t_{PLH}, t_{PHL} |
| 2.7 V | ≤ 10 MHz | 500 ns | ≤ 2.5 ns | 50 pF | 500 Ω | GND | 6 V | open |

12. Package outline

SSOP48: plastic shrink small outline package; 48 leads; body width 7.5 mm

SOT370-1

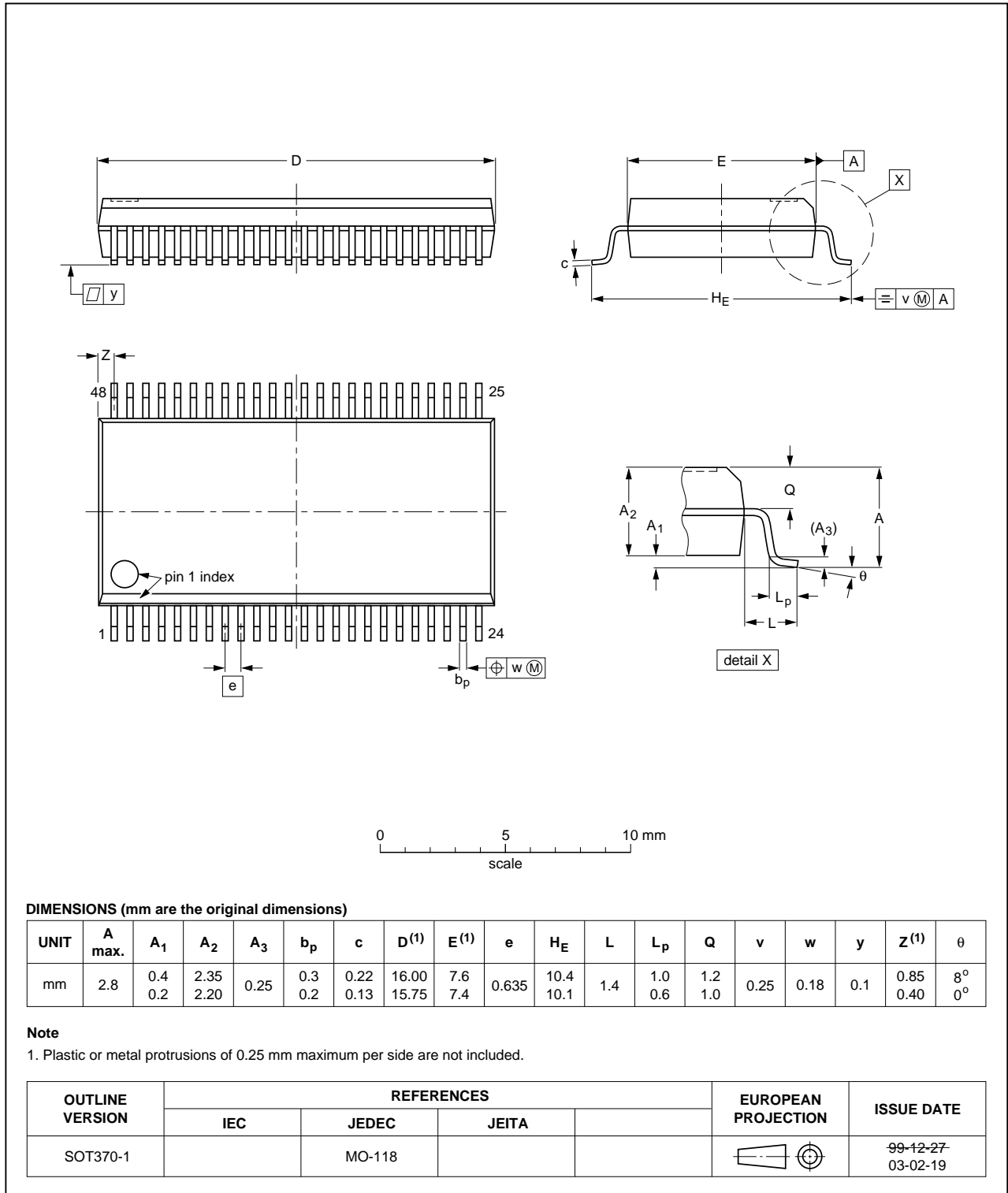


Fig 11. Package outline SOT370-1 (SSOP48)

TSSOP48: plastic thin shrink small outline package; 48 leads; body width 6.1 mm

SOT362-1

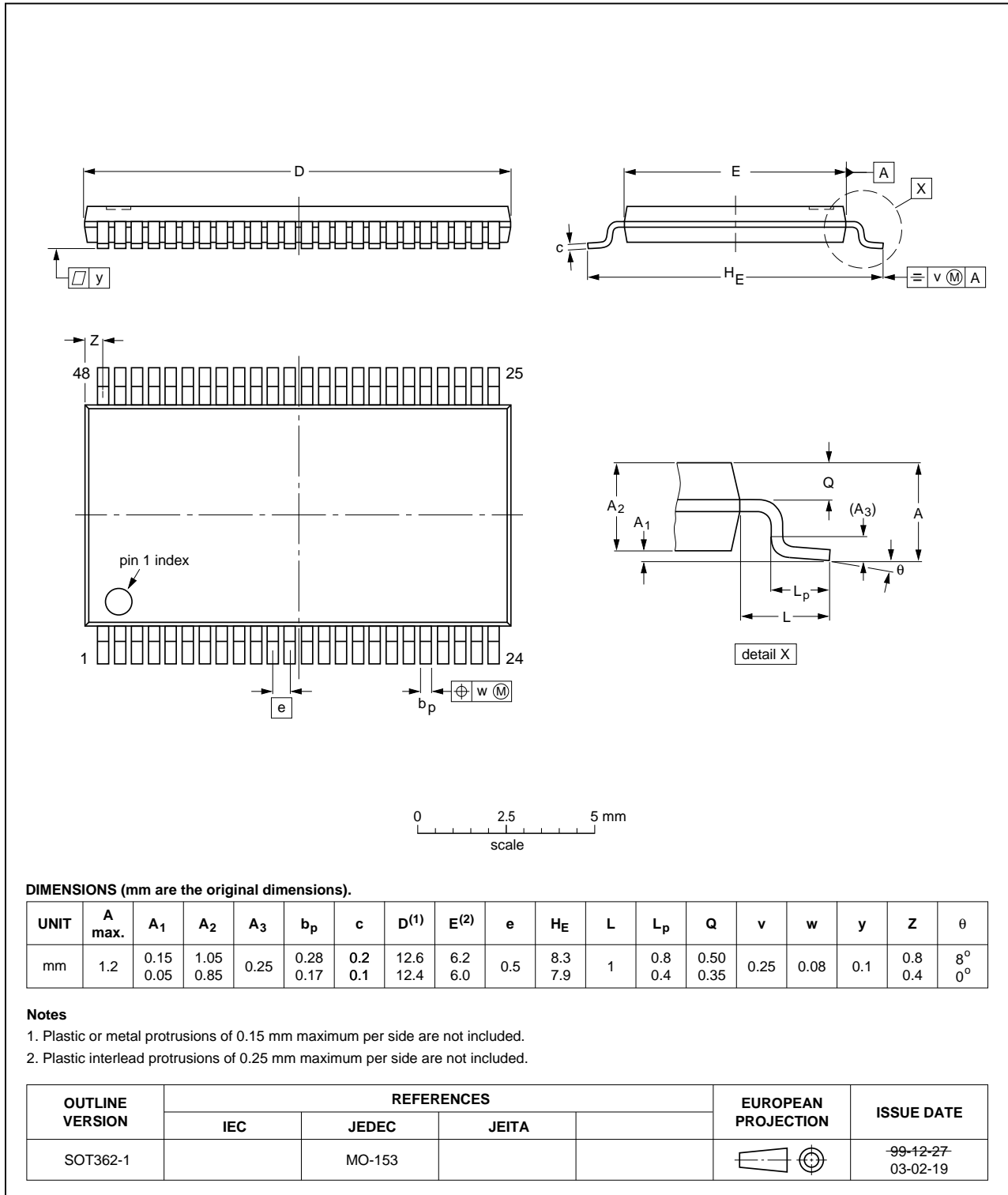


Fig 12. Package outline SOT362-1 (TSSOP48)

VFPGA56: plastic very thin fine-pitch ball grid array package; 56 balls; body 4.5 x 7 x 0.65 mm

SOT702-1

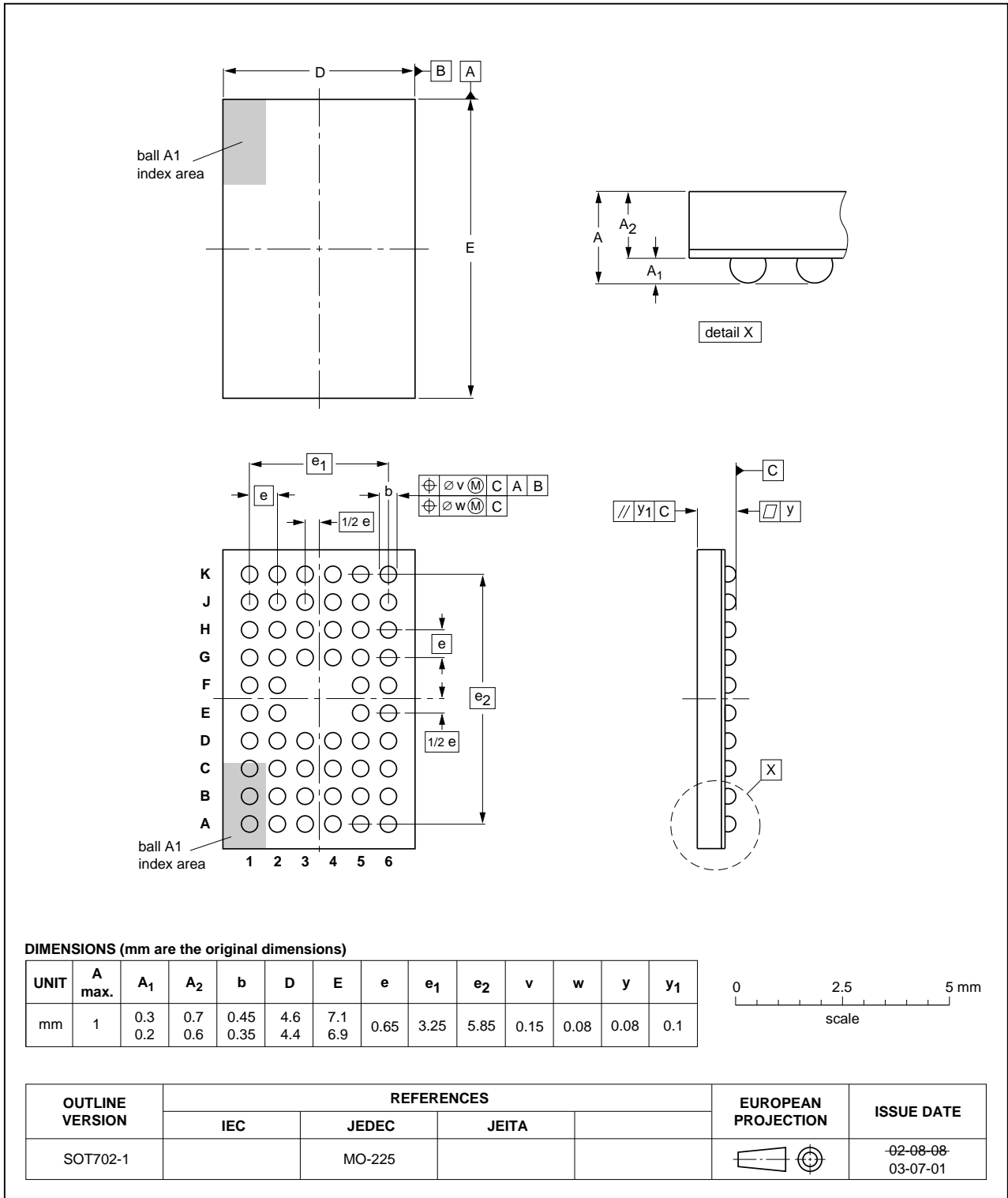


Fig 13. Package outline SOT702-1 (VFPGA56)

HXQFN60: plastic compatible thermal enhanced extremely thin quad flat package; no leads;
60 terminals; body 4 x 6 x 0.5 mm

SOT1134-2

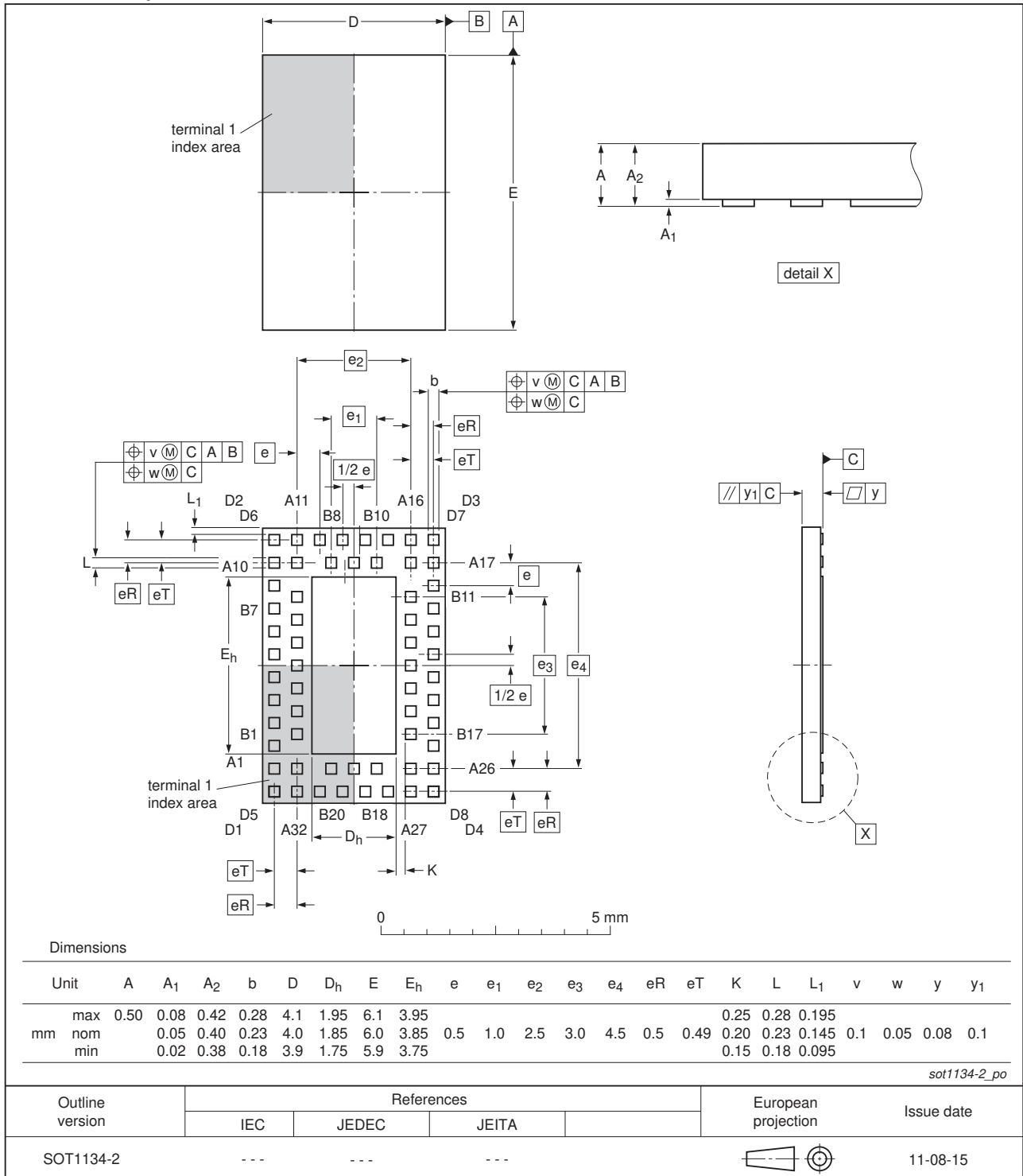


Fig 14. Package outline SOT1134-2 (HXQFN60)

13. Abbreviations

Table 10. Abbreviations

| Acronym | Description |
|---------|---|
| BiCMOS | Bipolar Complementary Metal Oxide Semiconductor |
| DUT | Device Under Test |
| ESD | ElectroStatic Discharge |
| HBM | Human Body Model |
| MM | Machine Model |
| TTL | Transistor-Transistor Logic |

14. Revision history

Table 11. Revision history

| Document ID | Release date | Data sheet status | Change notice | Supersedes |
|-----------------------|---|-----------------------|---------------|----------------------|
| 74LVT_LVTH16374A v.10 | 20120402 | Product data sheet | - | 74LVT_LVTH16374A v.9 |
| Modifications: | <ul style="list-style-type: none"> For type number 74LVTH16374ABX the sot code has changed to SOT1134-2. | | | |
| 74LVT_LVTH16374A v.9 | 20111122 | Product data sheet | - | 74LVT_LVTH16374A v.8 |
| Modifications: | <ul style="list-style-type: none"> Legal pages updated. | | | |
| 74LVT_LVTH16374A v.8 | 20110620 | Product data sheet | - | 74LVT_LVTH16374A v.7 |
| 74LVT_LVTH16374A v.7 | 20100322 | Product data sheet | - | 74LVT_LVTH16374A v.6 |
| 74LVT_LVTH16374A v.6 | 20100118 | product data sheet | - | 74LVT16374A v.5 |
| 74LVT16374A v.5 | 20040916 | product data sheet | - | 74LVT16374A v.4 |
| 74LVT16374A v.4 | 20021101 | product specification | - | 74LVT16374A v.3 |
| 74LVT16374A v.3 | 19991018 | product specification | - | 74LVT16374A v.2 |
| 74LVT16374A v.2 | 19980219 | product specification | - | - |

15. Legal information

15.1 Data sheet status

| Document status ^{[1][2]} | Product status ^[3] | Definition |
|-----------------------------------|-------------------------------|---|
| Objective [short] data sheet | Development | This document contains data from the objective specification for product development. |
| Preliminary [short] data sheet | Qualification | This document contains data from the preliminary specification. |
| Product [short] data sheet | Production | This document contains the product specification. |

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <http://www.nxp.com>.

15.2 Definitions

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17. Contents

| | | |
|-----------|---|-----------|
| 1 | General description | 1 |
| 2 | Features and benefits | 1 |
| 3 | Ordering information | 2 |
| 4 | Functional diagram | 2 |
| 5 | Pinning information | 3 |
| 5.1 | Pinning | 3 |
| 5.2 | Pin description | 5 |
| 6 | Functional description | 5 |
| 7 | Limiting values | 6 |
| 8 | Recommended operating conditions | 6 |
| 9 | Static characteristics | 7 |
| 10 | Dynamic characteristics | 8 |
| 11 | Waveforms | 9 |
| 12 | Package outline | 12 |
| 13 | Abbreviations | 16 |
| 14 | Revision history | 16 |
| 15 | Legal information | 17 |
| 15.1 | Data sheet status | 17 |
| 15.2 | Definitions | 17 |
| 15.3 | Disclaimers | 17 |
| 15.4 | Trademarks | 18 |
| 16 | Contact information | 18 |
| 17 | Contents | 19 |

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